Intel - EPF8282ALC84-4 Datasheet

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Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	26
Number of Logic Elements/Cells	208
Total RAM Bits	-
Number of I/O	68
Number of Gates	2500
Voltage - Supply	4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 70°C (TA)
Package / Case	84-LCC (J-Lead)
Supplier Device Package	84-PLCC (29.31x29.31)
Purchase URL	https://www.e-xfl.com/product-detail/intel/epf8282alc84-4

JTAG BST circuitry	Yes	No	Yes	Yes	No	Yes

...and More Features

- Peripheral register for fast setup and clock-to-output delay
- Fabricated on an advanced SRAM process
- Available in a variety of packages with 84 to 304 pins (see Table 2)
- Software design support and automatic place-and-route provided by the Altera® MAX+PLUS® II development system for Windows-based PCs, as well as Sun SPARCstation, HP 9000 Series 700/800, and IBM RISC System/6000 workstations
- Additional design entry and simulation support provided by EDIF 2 0 0 and 3 0 0 netlist files, library of parameterized modules (LPM), Verilog HDL, VHDL, and other interfaces to popular EDA tools from manufacturers such as Cadence, Exemplar Logic, Mentor Graphics, OrCAD, Synopsys, Synplicity, and Veribest

Table 2. FLEX 8000 Package Options & I/O Pin Count *Note (1)*

Device	84-Pin PLCC	100-Pin TQFP	144-Pin TQFP	160-Pin PQFP	160-Pin PGA	192-Pin PGA	208-Pin PQFP	225-Pin BGA	232-Pin PGA	240-Pin PQFP	280-Pin PGA	304-Pin RQFP
EPF8282A	68	78										
EPF8282AV		78										
EPF8452A	68	68		120	120							
EPF8636A	68			118		136	136					
EPF8820A			112	120		152	152	152				
EPF81188A							148		184	184		
EPF81500A										181	208	208

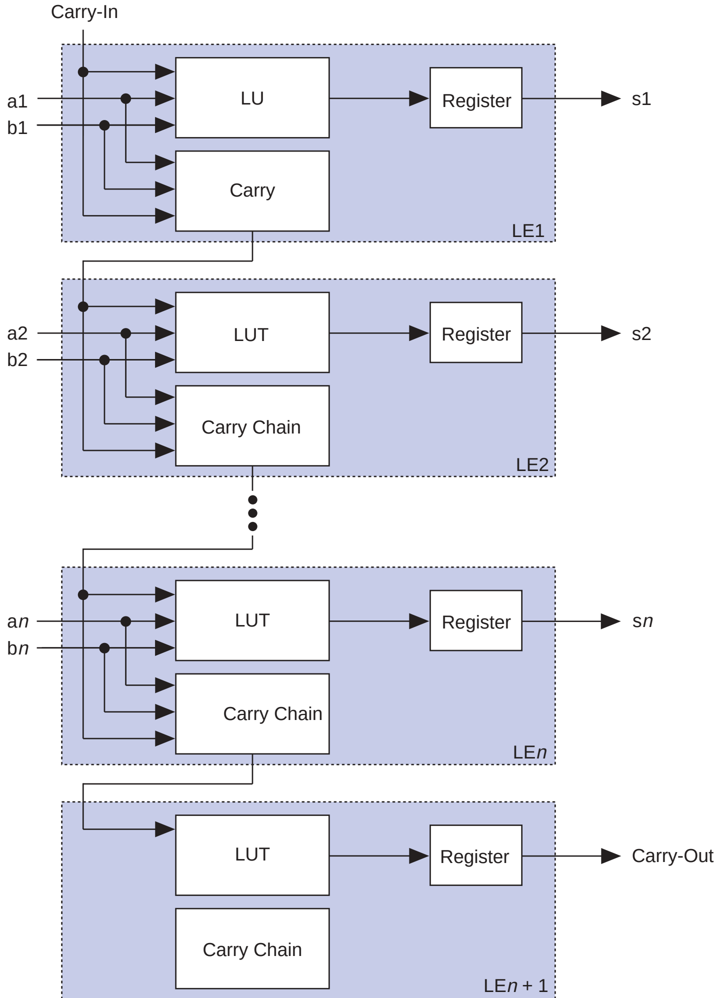
Note:

(1) FLEX 8000 device package types include plastic J-lead chip carrier (PLCC), thin quad flat pack (TQFP), plastic quad flat pack (PQFP), power quad flat pack (RQFP), ball-grid array (BGA), and pin-grid array (PGA) packages.

General Description

Altera's Flexible Logic Element MatriX (FLEX®) family combines the benefits of both erasable programmable logic devices (EPLDs) and field-programmable gate arrays (FPGAs). The FLEX 8000 device family is ideal for a variety of applications because it combines the fine-grained architecture and high register count characteristics of FPGAs with the high speed and predictable interconnect delays of EPLDs. Logic is implemented in LEs that include compact 4-input look-up tables (LUTs) and programmable registers. High performance is provided by a fast, continuous network of routing resources.

Figure 4. FLEX 8000 Carry Chain Operation



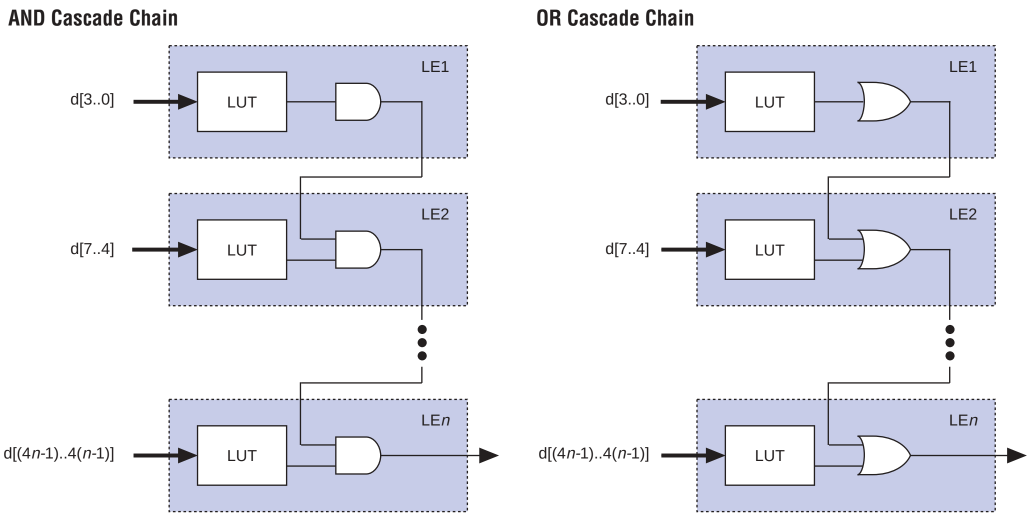
Cascade Chain

With the cascade chain, the FLEX 8000 architecture can implement functions that have a very wide fan-in. Adjacent LUTs can be used to compute portions of the function in parallel; the cascade chain serially connects the intermediate values. The cascade chain can use a logical `AND` or logical `OR` (via De Morgan's inversion) to connect the outputs of adjacent LEs. Each additional LE provides four more inputs to the effective width of a function, with a delay as low as 0.6 ns per LE.

The MAX+PLUS II Compiler can create cascade chains automatically during design processing; designers can also insert cascade chain logic manually during design entry. Cascade chains longer than eight LEs are automatically implemented by linking LABs together. The last LE of an LAB cascades to the first LE of the next LAB.

Figure 5 shows how the cascade function can connect adjacent LEs to form functions with a wide fan-in. These examples show functions of 4*n* variables implemented with *n* LEs. For a device with an A-2 speed grade, the LE delay is 2.4 ns; the cascade chain delay is 0.6 ns. With the cascade chain, 4.2 ns is needed to decode a 16-bit address.

Figure 5. FLEX 8000 Cascade Chain Operation



LE Operating Modes

The FLEX 8000 LE can operate in one of four modes, each of which uses LE resources differently. See Figure 6. In each mode, seven of the ten available inputs to the LE—the four data inputs from the LAB local interconnect, the feedback from the programmable register, and the carry-in and cascade-in from the previous LE—are directed to different destinations to implement the desired logic function. The three remaining inputs to the LE provide clock, clear, and preset control for the register. The MAX+PLUS II software automatically chooses the appropriate mode for each application. Design performance can also be enhanced by designing for the operating mode that supports the desired application.

Normal Mode

The normal mode is suitable for general logic applications and wide decoding functions that can take advantage of a cascade chain. In normal mode, four data inputs from the LAB local interconnect and the carry-in signal are the inputs to a 4-input LUT. Using a configurable SRAM bit, the MAX+PLUS II Compiler automatically selects the carry-in or the `DATA3` signal as an input. The LUT output can be combined with the cascade-in signal to form a cascade chain through the cascade-out signal. The `LE-Out` signal—the data output of the LE—is either the combinatorial output of the LUT and cascade chain, or the data output (`Q`) of the programmable register.

Arithmetic Mode

The arithmetic mode offers two 3-input LUTs that are ideal for implementing adders, accumulators, and comparators. One LUT provides a 3-bit function; the other generates a carry bit. As shown in Figure 6, the first LUT uses the carry-in signal and two data inputs from the LAB local interconnect to generate a combinatorial or registered output. For example, in an adder, this output is the sum of three bits: `a`, `b`, and the carry-in. The second LUT uses the same three signals to generate a carry-out signal, thereby creating a carry chain. The arithmetic mode also supports a cascade chain.

Up/Down Counter Mode

The up/down counter mode offers counter enable, synchronous up/down control, and data loading options. These control signals are generated by the data inputs from the LAB local interconnect, the carry-in signal, and output feedback from the programmable register. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. A 2-to-1 multiplexer provides synchronous loading. Data can also be loaded asynchronously with the clear and preset register control signals, without using the LUT resources.

Clearable Counter Mode

The clearable counter mode is similar to the up/down counter mode, but supports a synchronous clear instead of the up/down control; the clear function is substituted for the cascade-in signal in the up/down counter mode. Two 3-input LUTs are used: one generates the counter data, and the other generates the fast carry bit. Synchronous loading is provided by a 2-to-1 multiplexer, and the output of this multiplexer is `AND`ed with a synchronous clear.

Each LE in an LAB can drive up to two separate column interconnect channels. Therefore, all 16 available column channels can be driven by the LAB. The column channels run vertically across the entire device, and share access to LABs in the same column but in different rows. The MAX+PLUS II Compiler chooses which LEs must be connected to a column channel. A row interconnect channel can be fed by the output of the LE or by two column channels. These three signals feed a multiplexer that connects to a specific row channel. Each LE is connected to one 3-to-1 multiplexer. In an LAB, the multiplexers provide all 16 column channels with access to 8 row channels.

Each column of LABs has a dedicated column interconnect that routes signals out of the LABs into the column. The column interconnect can then drive I/O pins or feed into the row interconnect to route the signals to other LABs in the device. A signal from the column interconnect, which can be either the output of an LE or an input from an I/O pin, must transfer to the row interconnect before it can enter an LAB. Table 4 summarizes the FastTrack Interconnect resources available in each FLEX 8000 device.

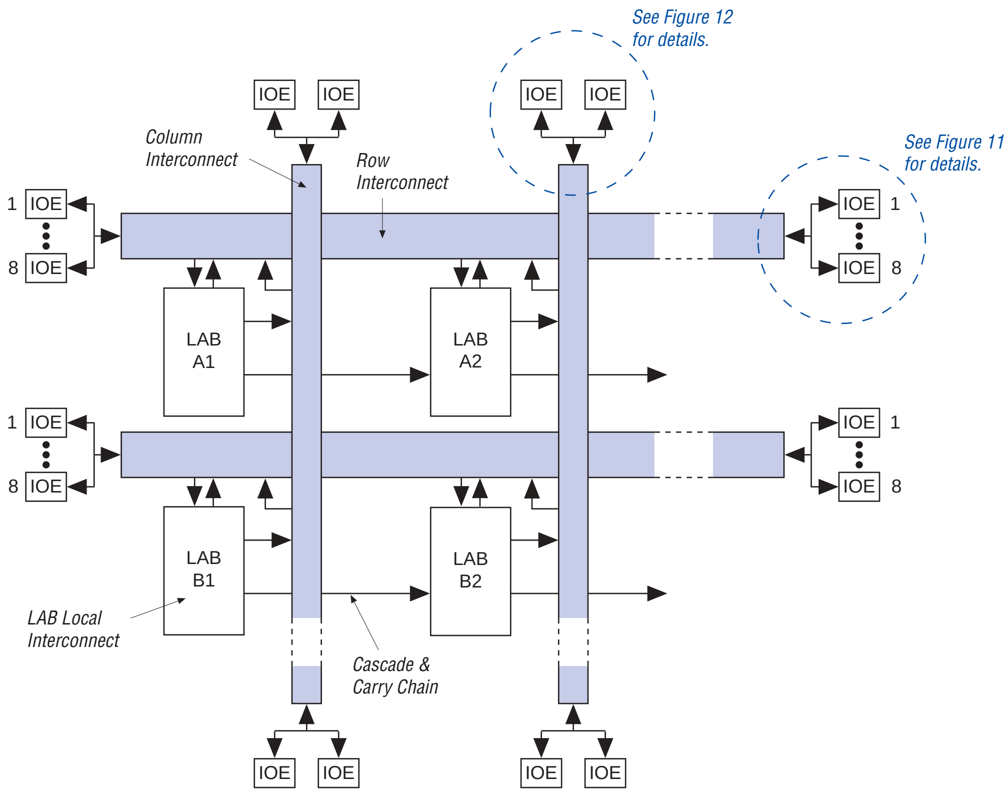
Table 4. FLEX 8000 FastTrack Interconnect Resources

Device	Rows	Channels per Row	Columns	Channels per Column
EPF8282A EPF8282AV	2	168	13	16
EPF8452A	2	168	21	16
EPF8636A	3	168	21	16
EPF8820A	4	168	21	16
EPF81188A	6	168	21	16
EPF81500A	6	216	27	16

Figure 9 shows the interconnection of four adjacent LABs, with row, column, and local interconnects, as well as the associated cascade and carry chains.

Figure 9. FLEX 8000 Device Interconnect Resources

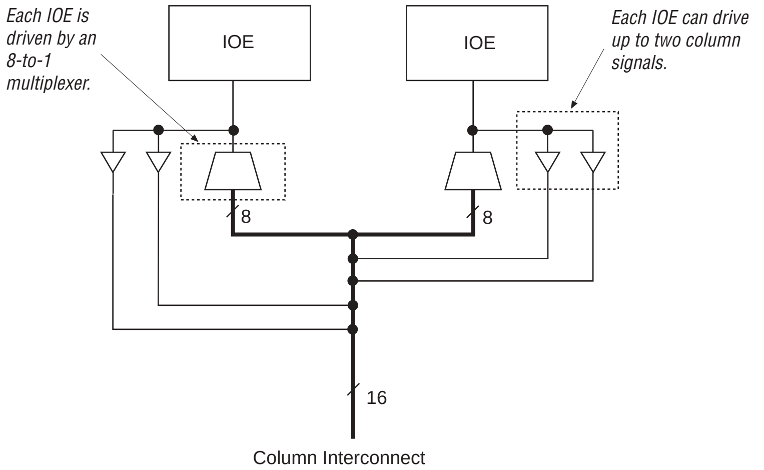
Each LAB is named according to its physical row (A, B, C, etc.) and column (1, 2, 3, etc.) position within the device.



I/O Element

An IOE contains a bidirectional I/O buffer and a register that can be used either as an input register for external data that requires a fast setup time, or as an output register for data that requires fast clock-to-output performance. IOEs can be used as input, output, or bidirectional pins. The MAX+PLUS II Compiler uses the programmable inversion option to automatically invert signals from the row and column interconnect where appropriate. Figure 10 shows the IOE block diagram.

Figure 12. FLEX 8000 Column-to-IOE Connections



In addition to general-purpose I/O pins, FLEX 8000 devices have four dedicated input pins. These dedicated inputs provide low-skew, device-wide signal distribution, and are typically used for global clock, clear, and preset control signals. The signals from the dedicated inputs are available as control signals for all LABs and I/O elements in the device. The dedicated inputs can also be used as general-purpose data inputs because they can feed the local interconnect of each LAB in the device.

Signals enter the FLEX 8000 device either from the I/O pins that provide general-purpose input capability or from the four dedicated inputs. The IOEs are located at the ends of the row and column interconnect channels.

I/O pins can be used as input, output, or bidirectional pins. Each I/O pin has a register that can be used either as an input register for external data that requires fast setup times, or as an output register for data that requires fast clock-to-output performance. The MAX+PLUS II Compiler uses the programmable inversion option to invert signals automatically from the row and column interconnect when appropriate.

The clock, clear, and output enable controls for the IOEs are provided by a network of I/O control signals. These signals can be supplied by either the dedicated input pins or by internal logic. The IOE control-signal paths are designed to minimize the skew across the device. All control-signal sources are buffered onto high-speed drivers that drive the signals around the periphery of the device. This "peripheral bus" can be configured to provide up to four output enable signals (10 in EPF81500A devices), and up to two clock or clear signals. Figure 13 on page 22 shows how two output enable signals are shared with one clock and one clear signal.

Table 8. JTAG Timing Parameters & Values

Symbol	Parameter	EPF8282A EPF8282AV EPF8636A EPF8820A EPF81500A		Unit
		Min	Max	
t_{JCP}	TCK clock period	100		ns
t_{JCH}	TCK clock high time	50		ns
t_{JCL}	TCK clock low time	50		ns
t_{JPSU}	JTAG port setup time	20		ns
t_{JPH}	JTAG port hold time	45		ns
t_{JPCO}	JTAG port clock to output		25	ns
t_{JPZX}	JTAG port high-impedance to valid output		25	ns
t_{JPXZ}	JTAG port valid output to high-impedance		25	ns
t_{JSSU}	Capture register setup time	20		ns
t_{JSH}	Capture register hold time	45		ns
t_{JSCO}	Update register clock to output		35	ns
t_{JSZX}	Update register high-impedance to valid output		35	ns
t_{JSXZ}	Update register valid output to high-impedance		35	ns

For detailed information on JTAG operation in FLEX 8000 devices, refer to *Application Note 39 (IEEE 1149.1 (JTAG) Boundary-Scan Testing in Altera Devices)*.

Generic Testing

Each FLEX 8000 device is functionally tested and specified by Altera. Complete testing of each configurable SRAM bit and all logic functionality ensures 100% configuration yield. AC test measurements for FLEX 8000 devices are made under conditions equivalent to those shown in Figure 15. Designers can use multiple test patterns to configure devices during all stages of the production flow.

Table 15. FLEX 8000 3.3-V Device DC Operating Conditions *Note (4)*

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{IH}	High-level input voltage		2.0		V_{CC} + 0.3	V
V_{IL}	Low-level input voltage		–0.3		0.8	V
V_{OH}	High-level output voltage	I_{OH} = –0.1 mA DC *(5)*	V_{CC} – 0.2			V
V_{OL}	Low-level output voltage	I_{OL} = 4 mA DC *(5)*			0.45	V
I_I	Input leakage current	V_I = V_{CC} or ground	–10		10	µA
I_{OZ}	Tri-state output off-state current	V_O = V_{CC} or ground	–40		40	µA
I_{CC0}	V_{CC} supply current (standby)	V_I = ground, no load *(6)*		0.3	10	mA

Table 16. FLEX 8000 3.3-V Device Capacitance *Note (7)*

Symbol	Parameter	Conditions	Min	Max	Unit
C_{IN}	Input capacitance	V_{IN} = 0 V, f = 1.0 MHz		10	pF
C_{OUT}	Output capacitance	V_{OUT} = 0 V, f = 1.0 MHz		10	pF

Notes to tables:

(1) See the *Operating Requirements for Altera Devices Data Sheet*.
(2) Minimum DC input voltage is –0.3 V. During transitions, the inputs may undershoot to –2.0 V or overshoot to 5.3 V for input currents less than 100 mA and periods shorter than 20 ns.
(3) The maximum V_{CC} rise time is 100 ms. V_{CC} must rise monotonically.
(4) These values are specified in Table 14 on page 29.
(5) The I_{OH} parameter refers to high-level TTL output current; the I_{OL} parameter refers to low-level TTL output current.
(6) Typical values are for T_A = 25° C and V_{CC} = 3.3 V.
(7) Capacitance is sample-tested only.

Figure 16 shows the typical output drive characteristics of 5.0-V FLEX 8000 devices. The output driver is compliant with ***PCI Local Bus Specification, Revision 2.2***.

Figure 16. Output Drive Characteristics of 5.0-V FLEX 8000 Devices (Except EPF8282A)

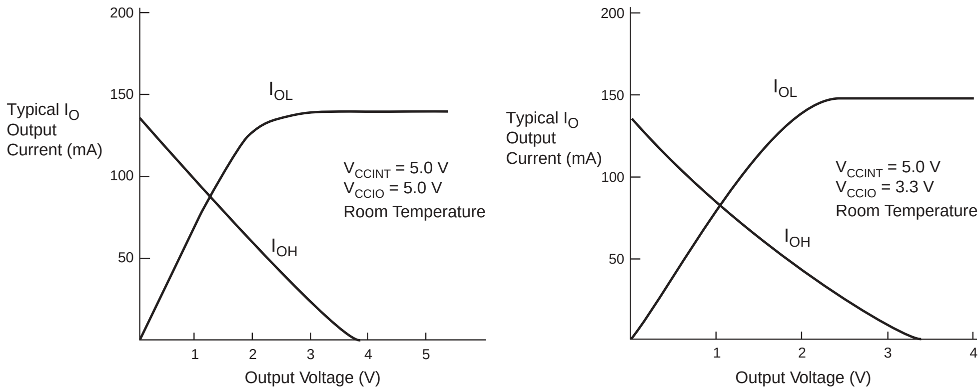


Figure 17 shows the typical output drive characteristics of 5.0-V EPF8282A devices. The output driver is compliant with ***PCI Local Bus Specification, Revision 2.2***.

Figure 17. Output Drive Characteristics of EPF8282A Devices with 5.0-V V_{CCIO}

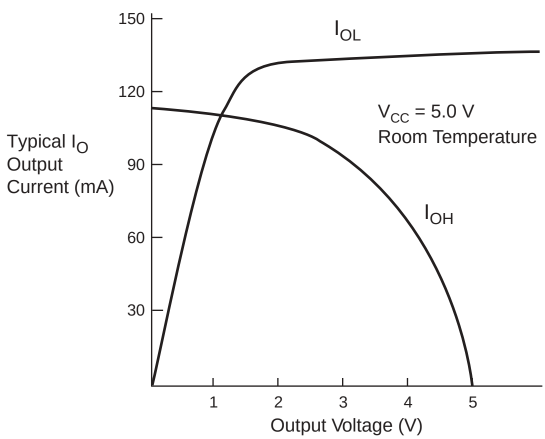


Figure 18 shows the typical output drive characteristics of EPF8282AV devices.

Table 19. FLEX 8000 Interconnect Timing Parameters *Note (1)*

Symbol	Parameter
$t_{LABCASC}$	Cascade delay between LEs in different LABs
$t_{LABCARRY}$	Carry delay between LEs in different LABs
t_{LOCAL}	LAB local interconnect delay
t_{ROW}	Row interconnect routing delay *(4)*
t_{COL}	Column interconnect routing delay
t_{DIN_C}	Dedicated input to LE control delay
t_{DIN_D}	Dedicated input to LE data delay *(4)*
t_{DIN_IO}	Dedicated input to IOE control delay

Table 20. FLEX 8000 External Reference Timing Characteristics *Note (5)*

Symbol	Parameter
$\mathbf{t_{DRR}}$	Register-to-register delay via 4 LEs, 3 row interconnects, and 4 local interconnects *(6)*
$\mathbf{t_{ODH}}$	Output data hold time after clock *(7)*

Notes to tables:
(1) Internal timing parameters cannot be measured explicitly. They are worst-case delays based on testable and external parameters specified by Altera. Internal timing parameters should be used for estimating device performance. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
(2) These values are specified in Table 10 on page 28 or Table 14 on page 29.
(3) For the t_{OD3} and t_{ZX3} parameters, V_{CCIO} = 3.3 V or 5.0 V.
(4) The t_{ROW} and t_{DIN_D} delays are worst-case values for typical applications. Post-compilation timing simulation or timing analysis is required to determine actual worst-case performance.
(5) External reference timing characteristics are factory-tested, worst-case values specified by Altera. A representative subset of signal paths is tested to approximate typical device applications.
(6) For more information on test conditions, see *Application Note 76* (*Understanding FLEX 8000 Timing*).
(7) This parameter is a guideline that is sample-tested only and is based on extensive device characterization. This parameter applies to global and non-global clocking, and for LE and I/O element registers.

The FLEX 8000 timing model shows the delays for various paths and functions in the circuit. See Figure 19. This model contains three distinct parts: the LE; the IOE; and the interconnect, including the row and column FastTrack Interconnect, LAB local interconnect, and carry and cascade interconnect paths. Each parameter shown in Figure 19 is expressed as a worst-case value in Tables 22 through 49. Hand-calculations that use the FLEX 8000 timing model and these timing parameters can be used to estimate FLEX 8000 device performance. Timing simulation or timing analysis after compilation is required to determine the final worst-case performance. Table 21 summarizes the interconnect paths shown in Figure 19.

For more information on timing parameters, go to *Application Note 76 (Understanding FLEX 8000 Timing)*.

Figure 19. FLEX 8000 Timing Model

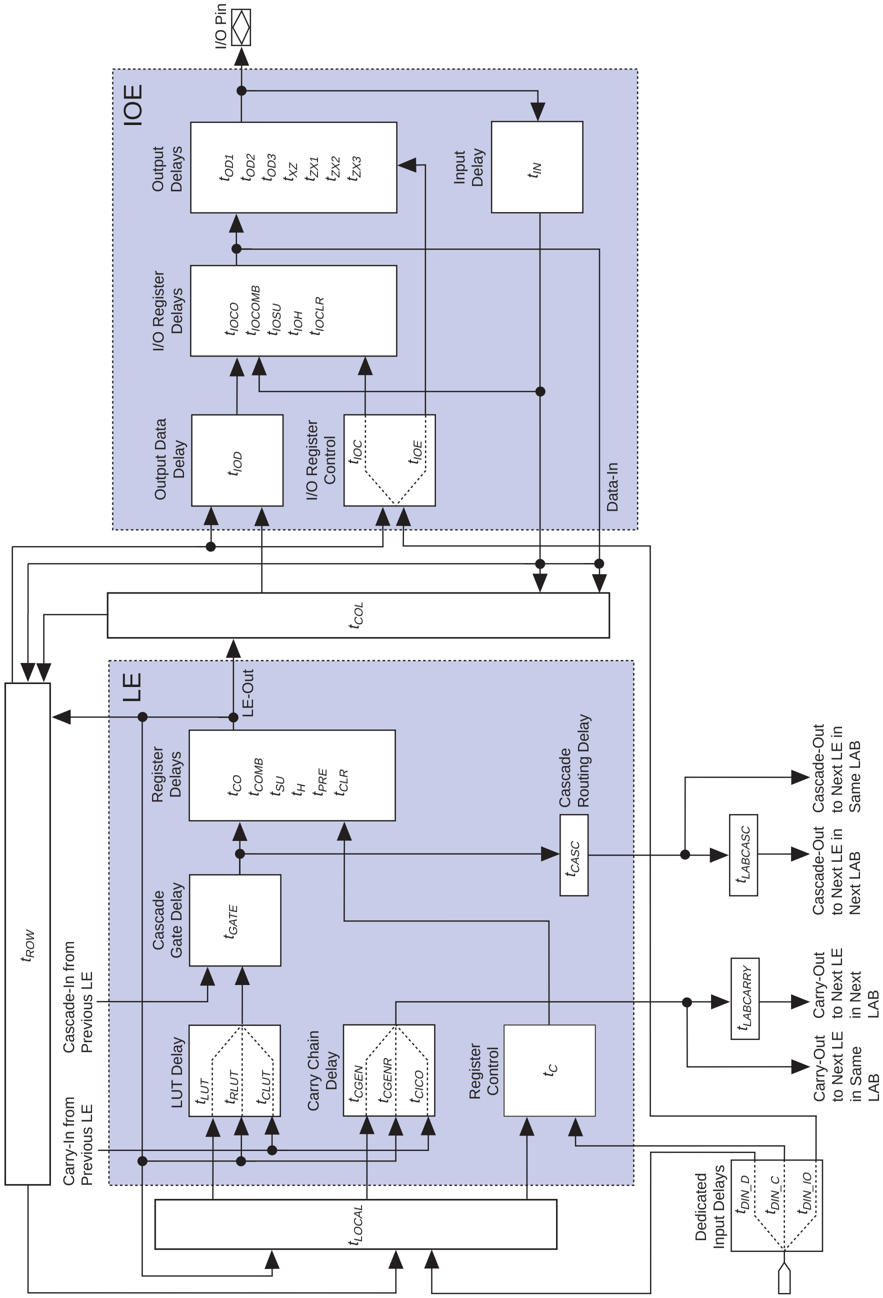


Table 21. FLEX 8000 Timing Model Interconnect Paths		
Source	**Destination**	**Total Delay**
LE-Out	LE in same LAB	t_{LOCAL}
LE-Out	LE in same row, different LAB	$t_{ROW} + t_{LOCAL}$
LE-Out	LE in different row	$t_{COL} + t_{ROW} + t_{LOCAL}$
LE-Out	IOE on column	t_{COL}
LE-Out	IOE on row	t_{ROW}
IOE on row	LE in same row	$t_{ROW} + t_{LOCAL}$
IOE on column	Any LE	$t_{COL} + t_{ROW} + t_{LOCAL}$

Tables 22 through 49 show the FLEX 8000 internal and external timing parameters.

Table 22. EPF8282A Internal I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		–		–		–	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		–		–		–	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 24. EPF8282A LE Timing Parameters							
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.5		3.2	ns
t_{CLUT}		0.0		0.0		0.0	ns
t_{RLUT}		0.9		1.1		1.5	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.5		0.7	ns
t_{CGENR}		0.9		1.1		1.5	ns
t_C		1.6		2.0		2.5	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.1		1.2		ns
t_H	0.9		1.1		1.5		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 25. EPF8282A External Timing Parameters							
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{DRR}		15.8		19.8		24.8	ns
t_{ODH}	1.0		1.0		1.0		ns

Table 34. EPF8636A I/O Element Timing Parameters							
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		1.6		1.9		2.2	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		1.9		2.1		2.3	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 35. EPF8636A Interconnect Timing Parameters							
Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.4		0.4	ns
$t_{LABCARRY}$		0.3		0.4		0.4	ns
t_{LOCAL}		0.5		0.5		0.7	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 36. EPF8636A LE Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.3		3.0	ns
t_{CLUT}		0.0		0.2		0.1	ns
t_{RLUT}		0.9		1.6		1.6	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.9		0.8	ns
t_{CGENR}		0.9		1.4		1.5	ns
t_{C}		1.6		1.8		2.4	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.0		1.1		ns
t_{H}	0.9		1.1		1.4		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 37. EPF8636A External Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$\mathbf{t_{DRR}}$		16.0		20.0		25.0	ns
$\mathbf{t_{ODH}}$	1.0		1.0		1.0		ns

Table 38. EPF8820A I/O Element Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		1.6		1.9		2.2	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		1.9		2.1		2.3	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 39. EPF8820A Interconnect Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$t_{LABCASC}$		0.3		0.3		0.4	ns
$t_{LABCARRY}$		0.3		0.3		0.4	ns
t_{LOCAL}		0.5		0.6		0.8	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 42. EPF81188A I/O Element Timing Parameters							
Symbol	**Speed Grade**						**Unit**
	A-2		**A-3**		**A-4**		
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	
t_{IOD}		0.7		0.8		0.9	ns
t_{IOC}		1.7		1.8		1.9	ns
t_{IOE}		1.7		1.8		1.9	ns
t_{IOCO}		1.0		1.0		1.0	ns
t_{IOCOMB}		0.3		0.2		0.1	ns
t_{IOSU}	1.4		1.6		1.8		ns
t_{IOH}	0.0		0.0		0.0		ns
t_{IOCLR}		1.2		1.2		1.2	ns
t_{IN}		1.5		1.6		1.7	ns
t_{OD1}		1.1		1.4		1.7	ns
t_{OD2}		1.6		1.9		2.2	ns
t_{OD3}		4.6		4.9		5.2	ns
t_{XZ}		1.4		1.6		1.8	ns
t_{ZX1}		1.4		1.6		1.8	ns
t_{ZX2}		1.9		2.1		2.3	ns
t_{ZX3}		4.9		5.1		5.3	ns

Table 43. EPF81188A Interconnect Timing Parameters							
Symbol	**Speed Grade**						**Unit**
	A-2		**A-3**		**A-4**		
	Min	**Max**	**Min**	**Max**	**Min**	**Max**	
$t_{LABCASC}$		0.3		0.3		0.4	ns
$t_{LABCARRY}$		0.3		0.3		0.4	ns
t_{LOCAL}		0.5		0.6		0.8	ns
t_{ROW}		5.0		5.0		5.0	ns
t_{COL}		3.0		3.0		3.0	ns
t_{DIN_C}		5.0		5.0		5.5	ns
t_{DIN_D}		7.0		7.0		7.5	ns
t_{DIN_IO}		5.0		5.0		5.5	ns

Table 44. EPF81188A LE Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
t_{LUT}		2.0		2.5		3.2	ns
t_{CLUT}		0.0		0.0		0.0	ns
t_{RLUT}		0.9		1.1		1.5	ns
t_{GATE}		0.0		0.0		0.0	ns
t_{CASC}		0.6		0.7		0.9	ns
t_{CICO}		0.4		0.5		0.6	ns
t_{CGEN}		0.4		0.5		0.7	ns
t_{CGENR}		0.9		1.1		1.5	ns
t_{C}		1.6		2.0		2.5	ns
t_{CH}	4.0		4.0		4.0		ns
t_{CL}	4.0		4.0		4.0		ns
t_{CO}		0.4		0.5		0.6	ns
t_{COMB}		0.4		0.5		0.6	ns
t_{SU}	0.8		1.1		1.2		ns
t_{H}	0.9		1.1		1.5		ns
t_{PRE}		0.6		0.7		0.8	ns
t_{CLR}		0.6		0.7		0.8	ns

Table 45. EPF81188A External Timing Parameters

Symbol	Speed Grade						Unit
	A-2		A-3		A-4		
	Min	Max	Min	Max	Min	Max	
$\mathbf{t_{DRR}}$		16.0		20.0		25.0	ns
$\mathbf{t_{ODH}}$	1.0		1.0		1.0		ns

Table 54. FLEX 8000 225-, 232-, 240-, 280- & 304-Pin Package Pin-Outs (Part 2 of 3)

Pin Name	225-Pin BGA EPF8820A	232-Pin PGA EPF81188A	240-Pin PQFP EPF81188A	240-Pin PQFP EPF81500A	280-Pin PGA EPF81500A	304-Pin RQFP EPF81500A
DATA4	A5	C7	198	194	W16	248
DATA3	B5	D7	196	193	W17	246
DATA2	E6	B5	194	190	V16	243
DATA1	D5	A3	191	189	U16	241
DATA0	C4	A2	189	187	V17	239
SDOUT *(3)*	K1	N2	135	136	F19	169
TDI	F15 *(4)*	–	–	63 *(14)*	B1 *(14)*	80 *(14)*
TDO	J2 *(4)*	–	–	117	C17	149
TCK *(6)*	J14 *(4)*	–	–	116 *(14)*	A19 *(14)*	148 *(14)*
TMS	J12 *(4)*	–	–	64 *(14)*	C2 *(14)*	81 *(14)*
TRST *(7)*	P14	–	–	115 *(14)*	A18 *(14)*	145 *(14)*
Dedicated Inputs *(10)*	F4, L1, K12, E15	C1, C17, R1, R17	10, 51, 130, 171	8, 49, 131, 172	F1, F16, P3, P19	12, 64, 164, 217
VCCINT (5.0 V)	F5, F10, E1, L2, K4, M12, P15, H13, H14, B15, C13	E4, H4, L4, P12, L14, H14, E14, R14, U1	20, 42, 64, 66, 114, 128, 150, 172, 236	18, 40, 60, 62, 91, 114, 129, 151, 173, 209, 236	B17, D3, D15, E8, E10, E12, E14, R7, R9, R11, R13, R14, T14	24, 54, 77, 144, 79, 115, 162, 191, 218, 266, 301
VCCIO (5.0 V or 3.3 V)	H3, H2, P6, R6, P10, N10, R14, N13, H15, H12, D12, A14, B10, A10, B6, C6, A2, C3, M4, R2	N10, M13, M5, K13, K5, H13, H5, F5, E10, E8, N8, F13	19, 41, 65, 81, 99, 116, 140, 162, 186, 202, 220, 235	17, 39, 61, 78, 94, 108, 130, 152, 174, 191, 205, 221, 235	D14, E7, E9, E11, E13, R6, R8, R10, R12, T13, T15	22, 53, 78, 99, 119, 137, 163, 193, 220, 244, 262, 282, 300